



# WG3: Radiation Damage & Extreme Fluences

Introduction to the WP – Scope – Community - Resources

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on behalf of the DRD3 proposal writing team





# WG3: Community composition



Status: 19.3.2023 [88 institutes]

- [\*] Not all institutes provided numbers No new strategic R&D included
- Extracted from research interest description in survey

### WG3: radiation damage & ultrahigh fluences

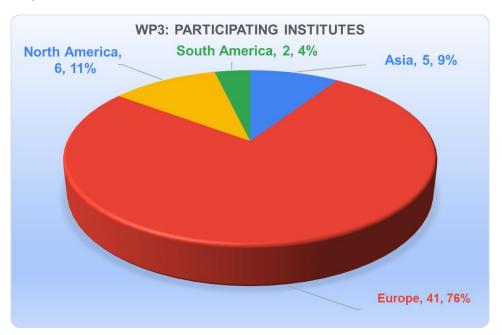
- 54 institutes (61% of 88\*) allocated FTEs to the "radiation damage studies" theme in the survey
  - Indicated FTE\*: 39 FTE senior personnel and 48 FTE post-doc, students
- 54 institutes
  - from 4 different continents

    Asia, Europe,

North America, South America

from 26 different countries

Brazil, Canada, Chile, Croatia, Czech Republic, Finland, France, Germany, India, Israel, Italy, Japan, Lithuania, Montenegro, Netherlands, Poland, Romania, Slovenia, Spain, Switzerland, Türkiye, UK, USA



A large part of the "DRD3 community" (≈ 80-90%) is interested in radiation damage tests or studies\*\*







## WG3: Needs for radhard devices





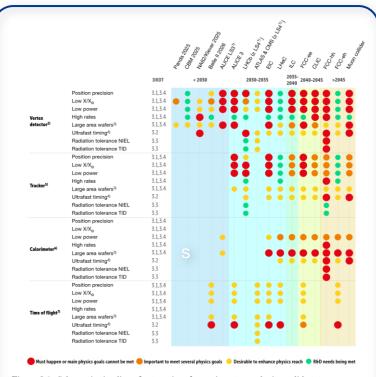
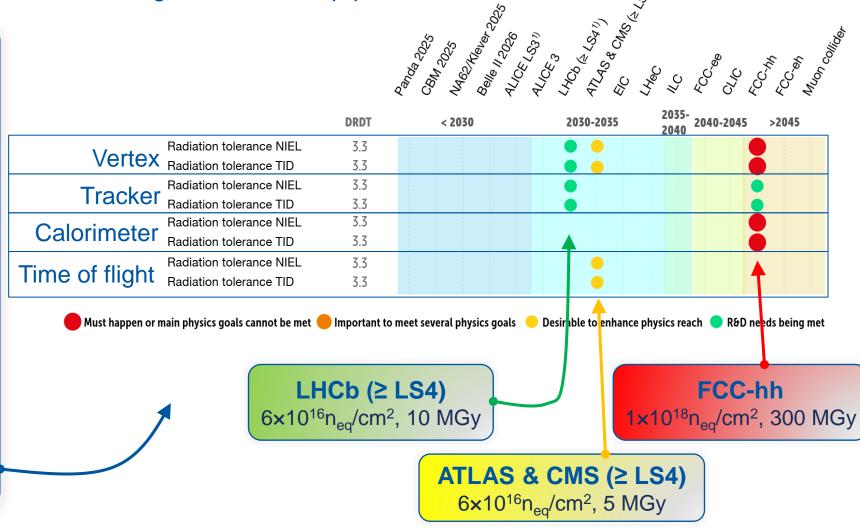


Figure 3.1: Schematic timeline of categories of experiments employing solid state sensors together with DRDTs and R&D tasks. The colour coding is linked not to the intensity of the required effort but to the potential impact on the physics programme of the experiment: Must happen or main physics goals cannot be met (red, largest dot); Important to meet several physics goals (orange, large dot); Desirable to enhance physics reach (yellow, medium dot); R&D needs being met (green, small dot); No further R&D required or not applicable (blank).

ECFA Detector R&D roadmap [CERN CDS]





## WG3: Recommendations for DRDT 3.3. DRD3



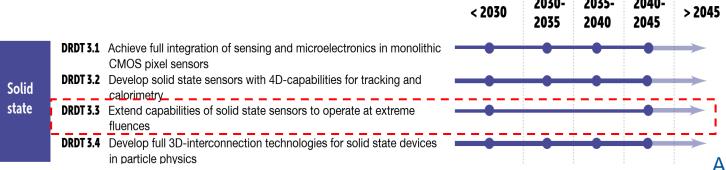
### ECFA R&D Roadmap

**DRDT 3.3. Extend capabilities of solid** state sensors to operate at extreme fluences

> Recommendations have been defined for DRDT3.3. and are fully in-line what we will propose:

ECFA Detector R&D roadmap [CERN CDS]

### DETECTOR RESEARCH AND DEVELOPMENT THEMES (DRDTs) & **DETECTOR COMMUNITY THEMES (DCTs)**



#### DRDT 3.3 - Sensors for extreme fluences.

- Measure the properties of silicon sensors in the fluence range  $1\times10^{16}\,\mathrm{n_{eq}\,cm^{-2}}$  to  $1\times10^{18}\,\mathrm{n_{eq}\,cm^{-2}}$ . Map the limit of 3D sensors and evolve their design to cope with the highest possible fluences;
- Optimise the simulation models with the measurements at high fluence;
- Develop simulation models based on microscopically measured point and cluster defects (instead of a model based on "effective trap levels");
- Explore the use of WBG semiconductors as radiation detectors at high fluences;
- Develop innovative 2D-materials that can offer high radiation hardness and operate at room temperature.

Activity shared within DRD3

with WG1 & WG2 sensors

> with WG4 **Simulation**

with WG6: Nonsilicon materials



## WG3: Expression of interest



interest description in survey

- Evaluate and/or improve radiation hardness of sensors [≈ 85%]
  - CMOS, LGAD, 3D, planar, .... (i.e. study radiation hardness of existing and newly developed sensor concepts)

see also WG1 & WG2 on sensors

- Explore the extreme fluence regime and/or study radiation damage to WBG sensors [≈ 65%]
  - Radiation damage up to extreme fluences (40 Institutes, 45%)
  - Radiation hardness of new materials (SiC: 26%, Diamond 17%, GaN 14%, Other 8%)

see also WG6 on WBG materials

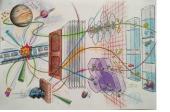
- Study the radiation induced formation of **microscopic defects** and defect properties [ ≈ 10%]
  - Defect spectroscopic measurements (10 Institutes, 11%)

see also WG5 on characterization tools

- Produce models to simulate radiation damage on material level [≈ 10%]
  - Modelling of primary damage (Geant4, SRIM, NIEL,...) (6 institutes)
  - Modelling of defect kinetics and defect engineering approaches (4 institutes)
- Produce models to simulate radiation damage on sensor level [≈ 17%, 15 Institutes]
  - Produce/Improve sensor damage parameterization models (i.e. like "Hamburg model")
  - Produce reliable TCAD models with defects to simulate radiation damaged sensors

**Note:** Number of institutes that want to use simulation tools (TCAD/MC/...) including radiation damage but not necessary want to develop the damage models itself is much higher (see session on simulation!)

see also WG4 on simulations



# WG3: Structuring of the WG



- WG structured in 3 areas for the discussion (and proposal?)
- WG closely related to all other WGs

#### **WG4: Simulations**

Need for simulations in all areas

- on the material level Geant4, TRIM, NIEL, DFT, KMC, ...
- on the device & system level TCAD, AP2, Signal & MC simulators, generic sensor parameter simulations (e.g. Hamburg model)
- extrapolation to extreme fluences do models still deliver reliable results?

### **WG5: Characterization techniques**

Need for tools in all areas

- on the material level EPR, FTIR, PL, DLTS, TSC, ...
- on the device & system level TCT, CV, IV, IBIC, test-beams, ....
- extrapolation to extreme fluences which tools still deliver reliable results? radiation facilities,...

### **WG3: Radiation Damage**

### **Radiation hardening** of material

understand fundamental damage process, defect formation, impact of defects on device performance (also non-silicon!), material and defect engineering

### **Radiation hardening** of devices and systems

understand device operation with radiation damage, device engineering

#### **Extreme fluences**

understand physics, possibilities for operation of detectors

#### WG6: Non-silicon based detectors

- Material & devices to be studied and understood as silicon in terms of radiation damage in all areas (simulations, material/sensor characterization, tool development)
- Developments for extreme fluence



### WG1 & WG2: Silicon based detectors

- Radiation hardness evaluation of all sensors with exposure to radiation (existing and newly developed sensors/sensor concepts)
- Developments for extreme fluence



#### **Synergies with other** application areas in radiation fields

Detectors for nuclear physics, space applications, fusion, medical applications, ...









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Talk.

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# WP3: Milestones (for discussion)



### **WG3: Radiation Damage**

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### Milestones for 3 years

- Material studies and understanding
  - Develop radiation damage models based on microscopically measured point and cluster defects for irradiation fluences up to  $10^{16} \, n_{eq}/cm^2$  [also as input for NIEL and TCAD simulations]
  - Develop defect engineered optimized devices: Refine and optimize radiation damage models
  - Non-silicon: Build up data sets on defect formation in non-silicon materials
- Devices and systems
  - Non-silicon: Build up dataset and produce improved or new models (i.e. parameterizations) for new materials including extreme radiation conditions; transfer of information from models to simulations
  - Improve radiation damage models for radiation levels up to the (HL-)LHC operation lifetime
    - sufficient test beam support required for this diverse program!
- Measure the properties of silicon/silicon sensors in the fluence range 10<sup>16</sup> to 10<sup>18</sup> n<sub>eq</sub>cm<sup>-2</sup>
  - Sensors: Map the operational limits for different device types
  - Material: Characterize the defects and the material properties (e.g. carrier mobility)
  - Material: Map limits of defect spectroscopic tools and explore/develop tools for extreme fluences
  - Deliver input data for models & simulation tools (microscopic and macroscopic level)

### Milestone for 6 years

reliable availability of facilities for 10<sup>18</sup> integrated fluence, charged and neutral.



